



# Eternal Semiconductor Inc.

## EN3401

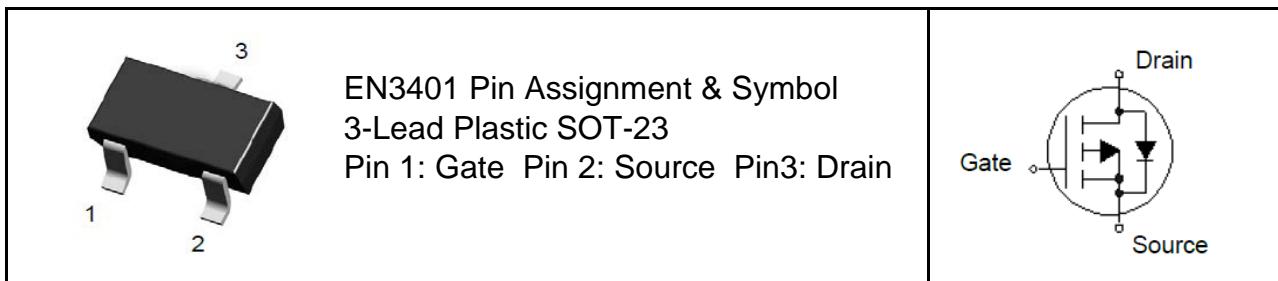
### P-Channel Enhancement-Mode MOSFET (-30V, -4.2A)

#### PRODUCT SUMMARY

$V_{DSS}$	$I_D$	$R_{DS(on)}$ (mΩ) Typ.
-30V	-4.2A	53 @ $V_{GS} = -10$ V, $I_D = -4.2$ A
		64 @ $V_{GS} = -4.5$ V, $I_D = -4.0$ A
		86 @ $V_{GS} = -2.5$ V, $I_D = -1.0$ A

#### Features

- Super high dense cell trench design for low RDS(on)
- Rugged and reliable
- SOT-23 package
- Lead (Pb)-free and halogen-free



#### Absolute Maximum Ratings ( $T_A = 25^\circ\text{C}$ , unless otherwise noted)

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_D$	Drain Current (Continuous)	-4.2	A
$I_{DM}$	Drain Current (Pulsed) <sup>a</sup>	-30	A
$P_D$	Total Power Dissipation @ $T_A = 25^\circ\text{C}$	-2.2	W
$I_S$	Maximum Diode Forward Current	1.25	A
$T_j, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to +150	°C
$R_{QJA}$	Thermal Resistance Junction to Ambient (PCB mounted) <sup>b</sup>	140	°C/W

a: Repetitive Rating: Pulse width limited by the maximum junction temperature.

b: 1-in<sup>2</sup> 2oz Cu PCB board



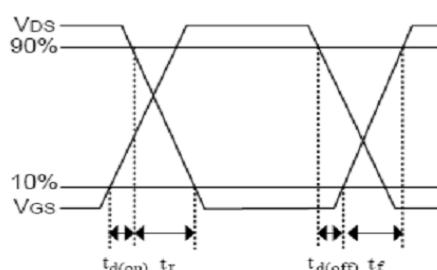
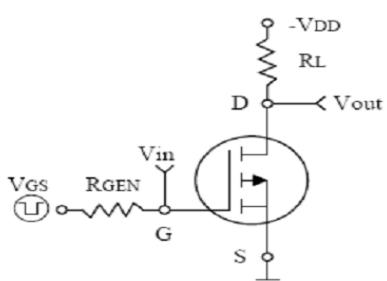
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**Electrical Characteristics** ( $T_A=25^\circ C$ , unless otherwise noted)

Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
<b>• Off Characteristics</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-30V, V_{GS}=0V$	-	-	1	$\mu A$
$I_{GSS}$	Gate-Body Leakage Current	$V_{GS}=\pm 12V, V_{DS}=0V$	-	-	$\pm 100$	nA
<b>• On Characteristics</b>						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=-250\mu A$	-0.7		-1.3	V
$R_{DS(on)}$	Drain-Source On-State Resistance	$V_{GS}=-10V, I_D=-4.2A$	-	53	60	$m\Omega$
		$V_{GS}=-4.5V, I_D=-4A$		64	75	
		$V_{GS}=-2.5V, I_D=1A$	-	86	120	
<b>• Dynamic Characteristics</b>						
$C_{iss}$	Input Capacitance	$V_{DS}=-15V, V_{GS}=0V, f=1MHz$	-	1325	-	PF
$C_{oss}$	Output Capacitance		-	172	-	
$C_{rss}$	Reverse Transfer Capacitance		-	140	-	
<b>• Switching Characteristics</b>						
$Q_g$	Total Gate Charge	$V_{DS}=-15V, I_D=-1A, V_{GS}=-10V$	-	27.8	-	nC
$Q_{gs}$	Gate-Source Charge		-	3.2	-	
$Q_{gd}$	Gate-Drain Charge		-	2.72	-	
$t_{d(on)}$	Turn-on Delay Time	$V_{DD}=-15V, R_L=15\Omega, I_D=1A,$ $VGEN=-4.5V, RG=10\Omega$	-	5	-	nS
$t_r$	Turn-on Rise Time		-	3	-	
$t_{d(off)}$	Turn-off Delay Time		-	30	-	
$t_f$	Turn-off Fall Time		-	10	-	
<b>• Drain-Source Diode Characteristics</b>						
$V_{SD}$	Drain-Source Diode Forward	$V_{GS}=0V, I_S=-1A$	-	-	-1	V

Note: Pulse Test: Pulse Width  $\leq 300\mu s$ , Duty Cycle  $\leq 2\%$



Switching Test Circuit and Swithcing Waveforms



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Typical Characteristics Curves (Ta=25°C, unless otherwise note)

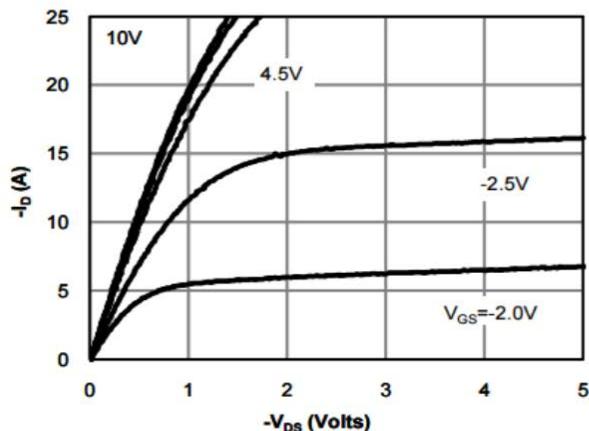


Fig 1: On-Resistance Characteristics

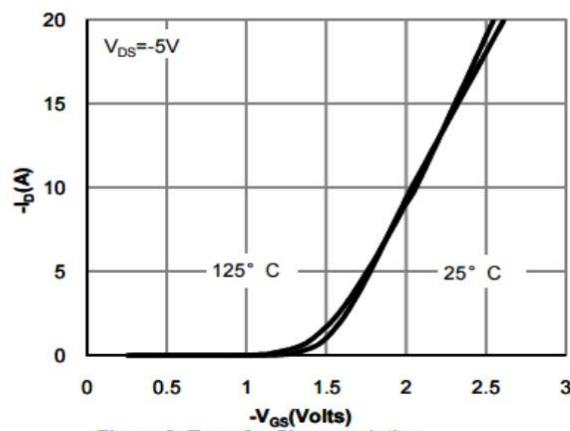


Figure 2: Transfer Characteristics

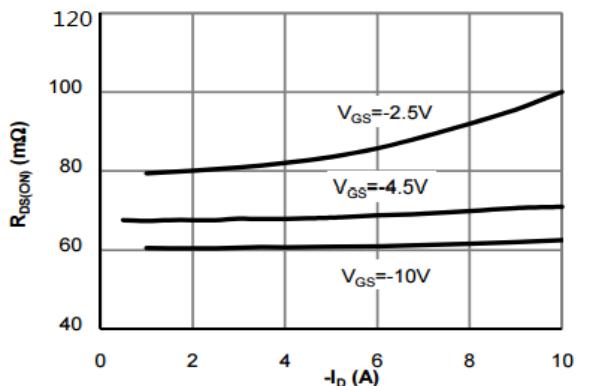


Figure 3: On-Resistance vs. Drain Current and Gate

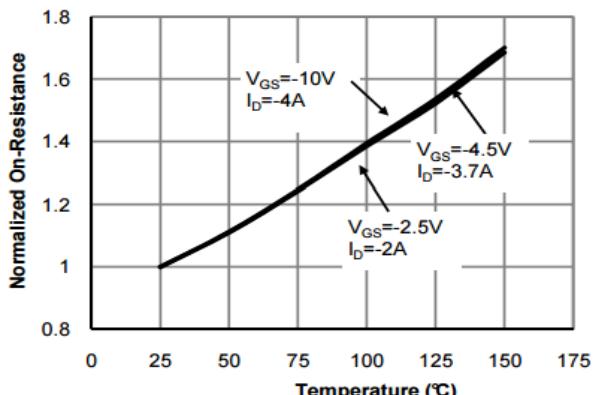


Figure 4: On-Resistance vs. Junction Temperature

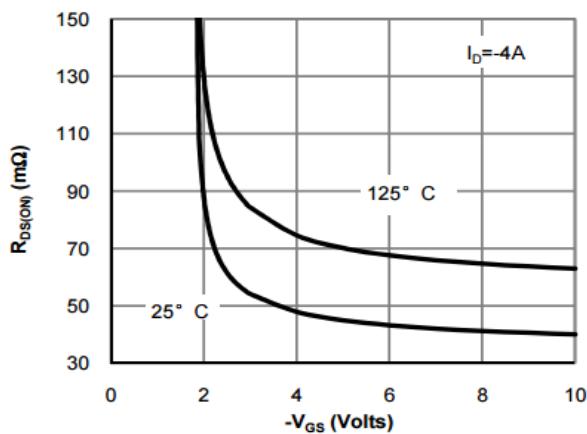


Figure 5: On-Resistance vs. Gate-Source Voltage

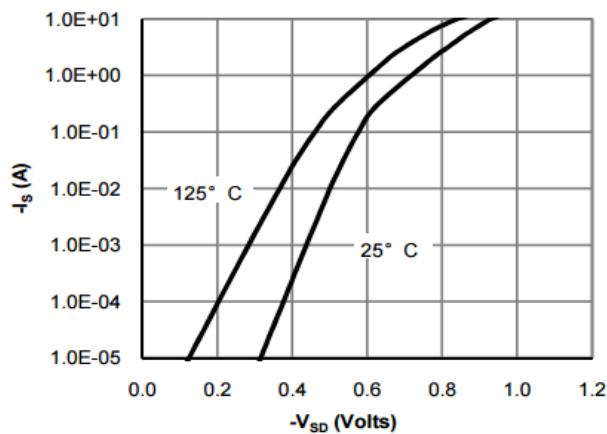


Figure 6: Body-Diode Characteristics

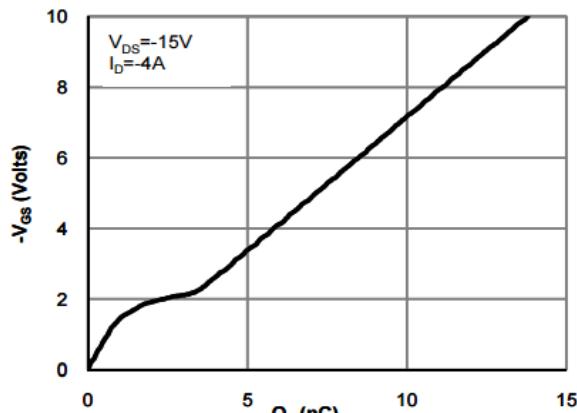


Figure 7: Gate-Charge Characteristics

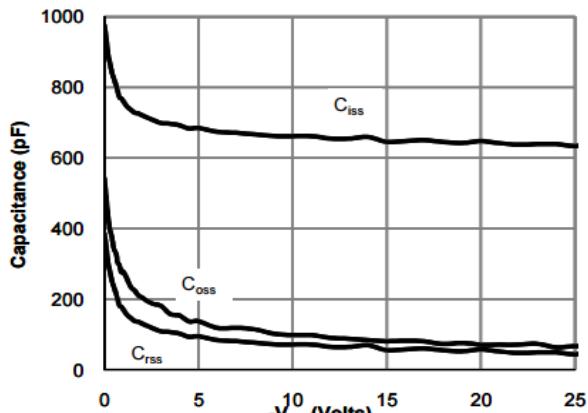


Figure 8: Capacitance Characteristics

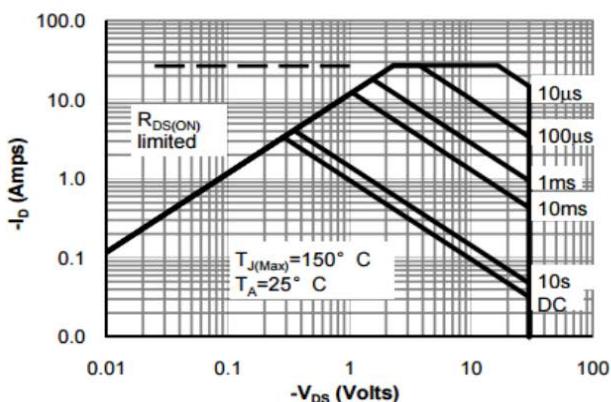


Figure 9: Maximum Forward Biased Safe Operating Area

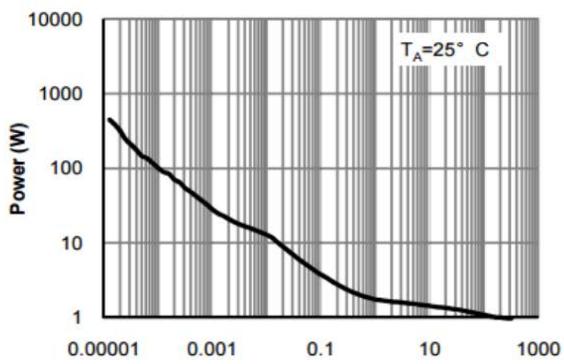


Figure 10: Single Pulse Power Rating Junction-to-Ambient

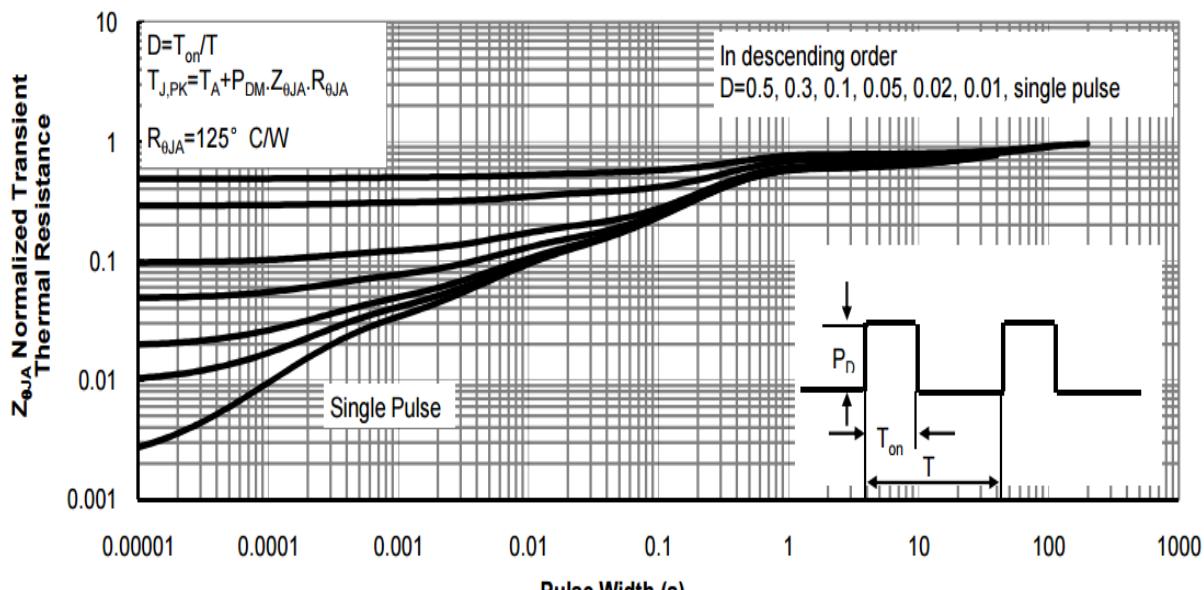


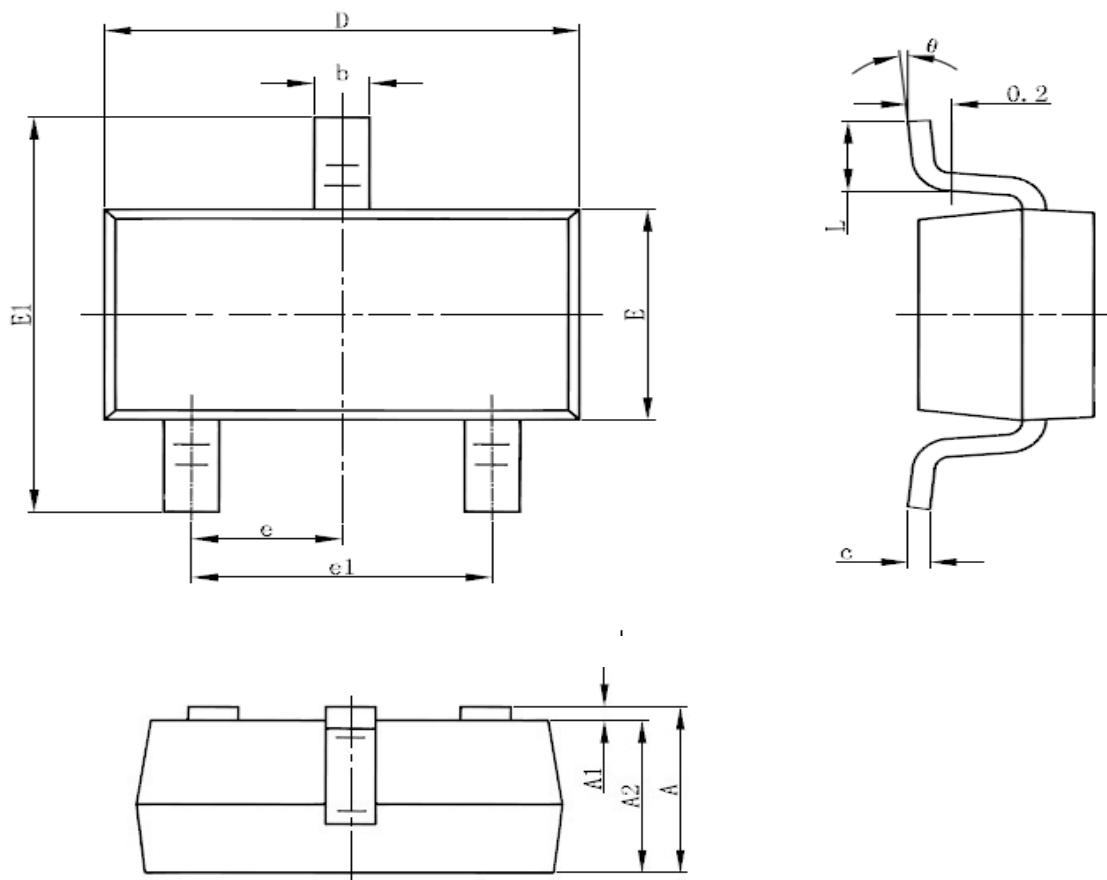
Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



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### SOT-23 PACKAGE OUTLINE DIMENSIONS



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950 TYP.		0.037 TYP.	
e1	1.800	2.000	0.071	0.079
L	0.550 REF.		0.022 REF.	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°